## Application/Control No. Applicant(s)/Patent Under Reexamination 10/692,501 SHAPPELL ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Shew-Fen Lin 2166 U.S. PATENT DOCUMENTS **Document Number** Date Classification Country Code-Number-Kind Code Name MM-YYYY \* 358/400 US-5,754,306 A 05-1998 Taylor et al. US-2002/0052885 A1 05-2002 707/200 В Levy, Kenneth L. US-2002/0174372 A1 11-2002 713/400 С Venkataraman, Buvana US-2004/0103280 A1 05-2004 Balfanz et al. 713/169 D US-6,938,042 B2 08-2005 Aboulhosn et al. 707/10 Ε US-F US-G US-Н US-1 US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS Document Number Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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